

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10583507	CHEN ET AL.
	Examiner	Art Unit
	Benny Lee	2817

SEARCHED

Class	Subclass	Date	Examiner
333	26	4 March 2009	BTL
333	34, 21A	6 March 2009	BTL

SEARCH NOTES

Search Notes	Date	Examiner

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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